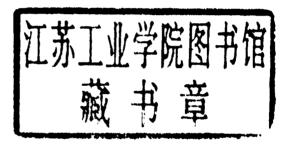
# Spectroscopy in Process Analysis

# **Spectroscopy in Process Analysis**

Edited by

JOHN M. CHALMERS
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First published 2000 Copyright © 2000 Sheffield Academic Press

Published by Sheffield Academic Press Ltd Mansion House, 19 Kingfield Road Sheffield S11 9AS, England

ISBN 1-84127-040-7

Published in the U.S.A. and Canada (only) by CRC Press LLC 2000 Corporate Blvd., N.W. Boca Raton, FL 33431, U.S.A. Orders from the U.S.A. and Canada (only) to CRC Press LLC

U.S.A. and Canada only: ISBN 0-8493-9747-2

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Printed on acid-free paper in Great Britain by Bookcraft Ltd, Midsomer Norton, Bath

## British Library Cataloguing-in-Publication Data:

A catalogue record for this book is available from the British Library

## Library of Congress Cataloging-in-Publication Data:

Spectroscopy in process analysis / edited by John M. Chalmers.

p. cm.
 Includes bibliographical references and index.

ISBN 0-8493-9747-2 (alk. paper)

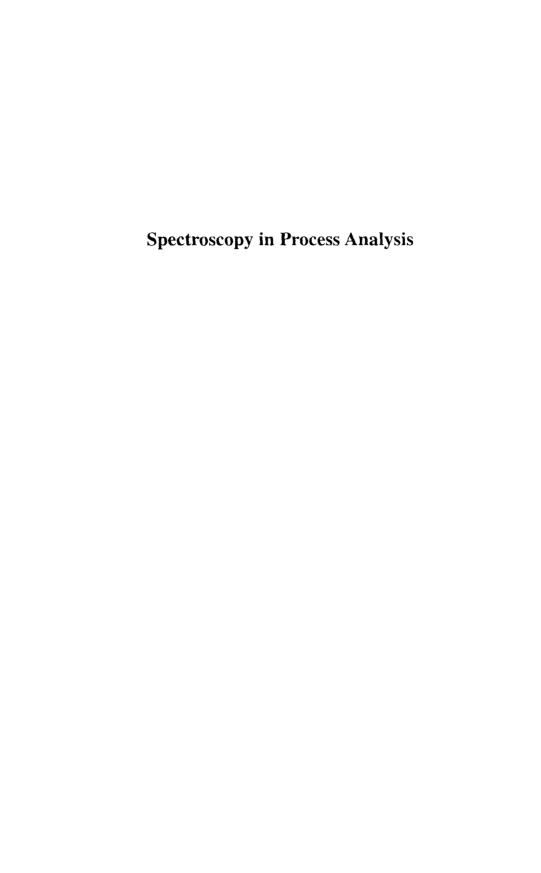
1. Spectrum analysis. 2. Chemical p

2. Chemical process control. I. Chalmers,

John M.

TP155.75.S82 1999

660'.2--dc21 99-39057 CIP



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## **Preface**

The planning of a reference volume in an area as important as spectroscopy in process analysis requires certain structural decisions. One obvious option is to organise the coverage by specific industries, such as food, pharmaceuticals, chemicals, etc. This approach was rejected, as it was thought likely to invite repetition of the more commonly used spectroscopic techniques, sampling procedures and chemometric methods. A technique-based work, in which each of the major spectroscopic disciplines employed in process analysis is considered by an experienced practitioner in the field, was thought likely to provide a more balanced and informative volume. There are many similarities in the challenges and problems of sampling, whether one is analysing milk or a polymer dispersion, interrogating a detergent or a formulated drug powder, or monitoring a web, fibre or film line.

This volume includes specialist chapters on multivariate analysis (chemometrics) and sampling and integration, both likely to be key elements in cost-effective and robust on-line process analysis. Many hopes have floundered because of failure to appreciate the initial messages of the statistics associated with regressional analysis. On the other hand, precise, well-worked methods developed by a spectroscopist from the perspective of a research laboratory may be laughed out of the process plant as totally inappropriate to that environment and skill-base.

At a time when cost- and time-effective process spectroscopy is becoming an issue of increasing importance within the chemical industry, this volume should provide a valuable source of up-to-date information on technological advances in the area. It complements more general works on process analytical chemistry.

John M. Chalmers

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#### 1 Introduction

John M. Chalmers

#### 1.1 Overview

In a volume discussing essentially the *status quo* for the more commonly used spectroscopic techniques in process analysis, it is interesting first to reflect on how things have progressed over the recent past. In doing so, one realises how rapidly today's technology has enabled adaptation of many of yesterday's research measurement science techniques into robust, versatile systems suitable as process analysers and monitors.

Hirschfeld *et al.* [1], in a 1984 review illustrating the use of on-line instrument utilisation in process control, showed the following categorisation for spectroscopic techniques at that time.

- Widespread:
  - Ultraviolet-visible colorimetry Infrared absorption (filter)
- Occasional:

Fluorimetry
Infrared absorption (scanning)
Ultraviolet absorption

Potential:

Chemiluminescence

Raman

Infrared emission

Nuclear magnetic resonance

Near-infrared reflectance.

In 1986, in his book *Process Analyzer Technology*, Clevett wrote:

'Spectroscopy has probably seen as much change as any other analytical technique in recent years. It is a wide and varied subject, each individual technique almost a specialist technology in its own right. During the past decade, we have also seen major developments in on-line spectrometric analyzers; techniques such as mass spectrometry and X-ray fluorescence, hitherto restricted to the laboratory, have now migrated into the on-line process field. Such development is still proceeding today and will almost certainly continue in the future.'

How true was this prediction! The use of spectroscopy for industrial process on-line analysis has and continues to grow steadily, both from

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#### 1 Introduction

John M. Chalmers

#### 1.1 Overview

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